US00D766753S

(12) United States Design Patent
Ishii et al.

(10) **Patent No.: US D766,753 S**
(45) **Date of Patent: ** Sep. 20, 2016**

(54) **OPTICAL MEASURING THEDOLITE USING LIGHT WAVE**

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(**) Term: **15 Years**

(21) Appl. No.: **29/529,894**

(22) Filed: **Jun. 11, 2015**

(30) **Foreign Application Priority Data**

Mar. 20, 2015 (JP) 2015-006085

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/66**

(58) **Field of Classification Search**
USPC D10/66
CPC G01C 1/00–1/14
See application file for complete search history.

(56) **References Cited**

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(57) **CLAIM**

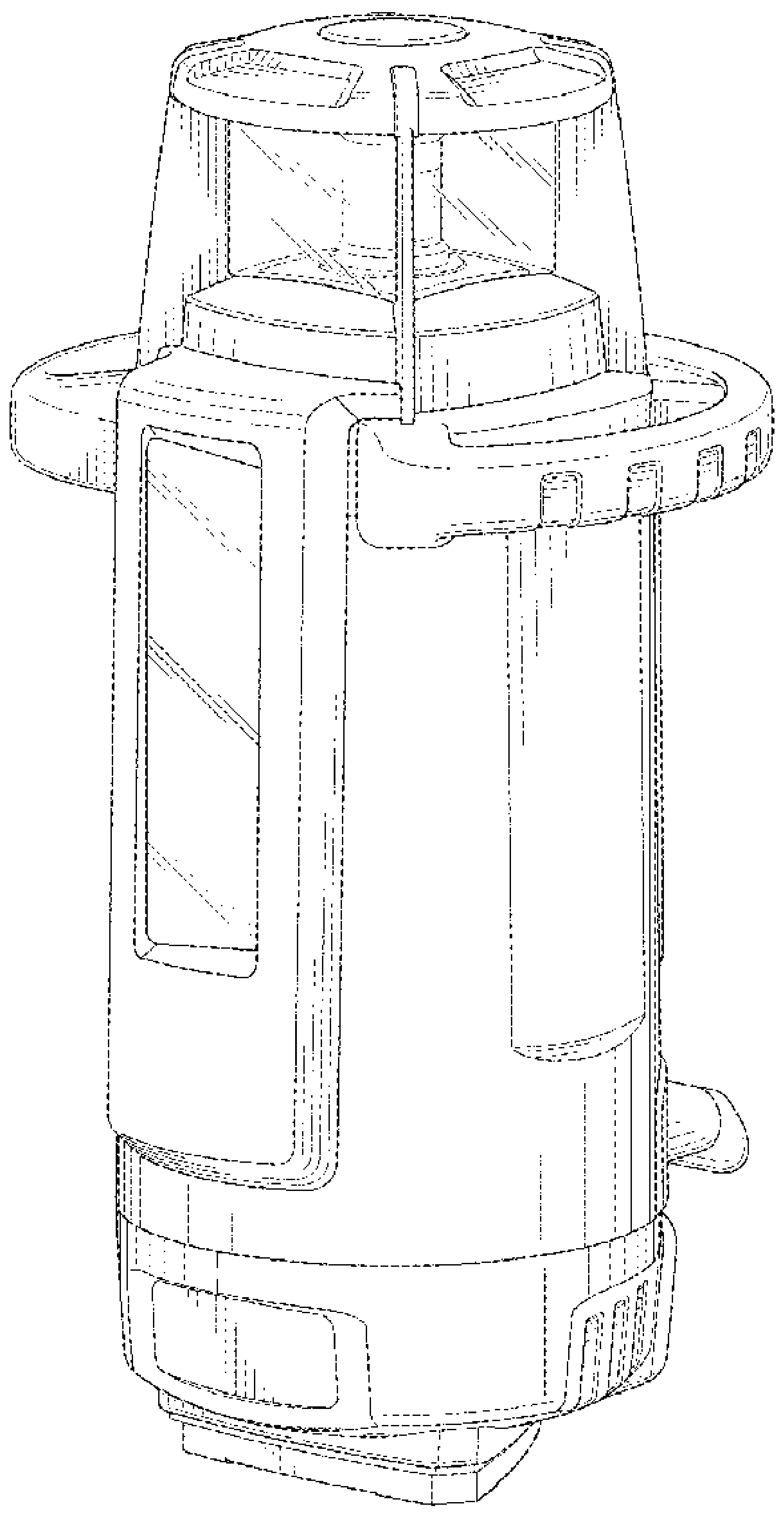
The ornamental design for an optical measuring theodolite using light wave, as shown and described.

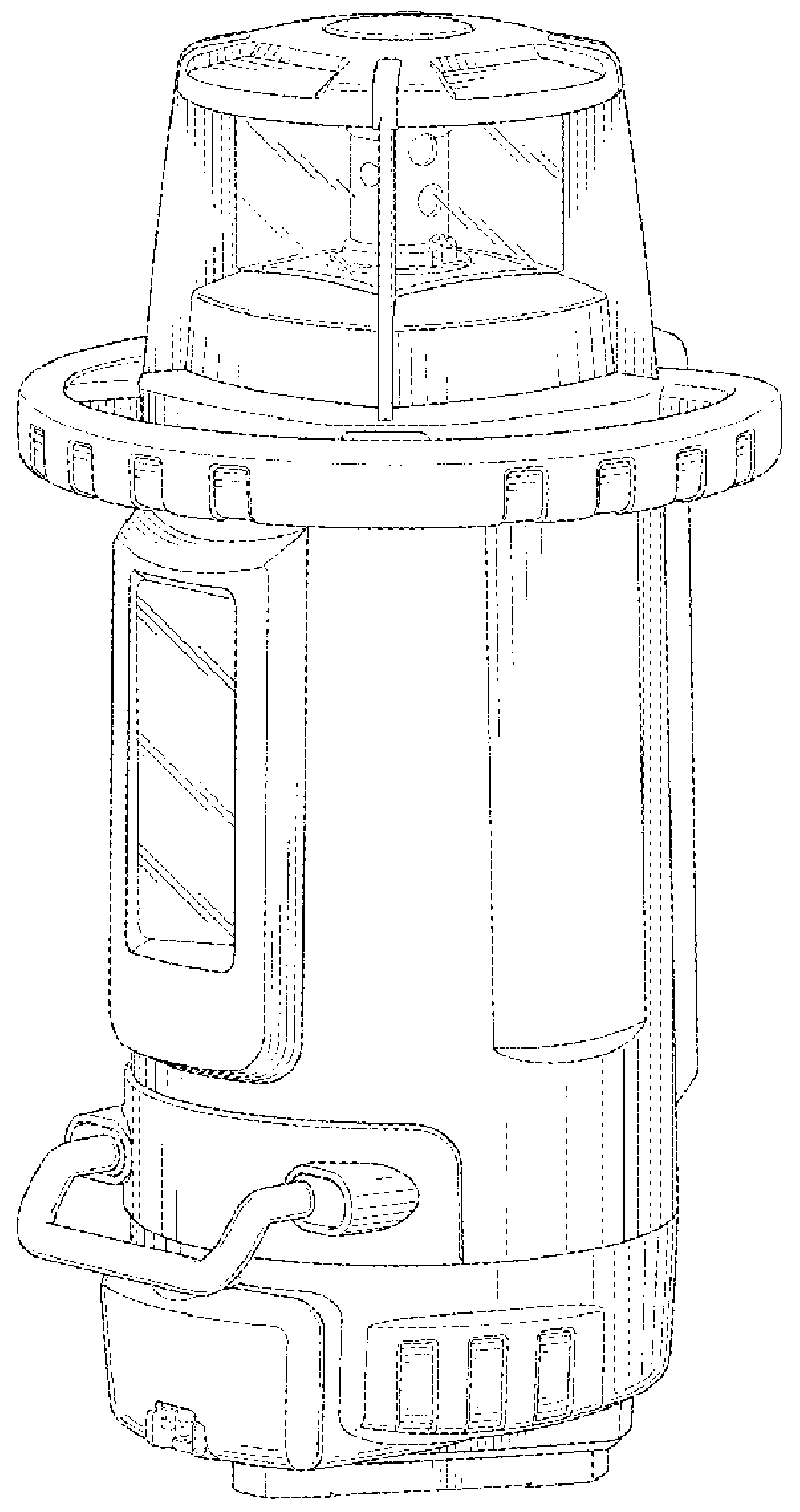
DESCRIPTION

FIG. **1** is a front elevational view of the optical measuring theodolite using light wave;
FIG. **2** is a rear elevational view thereof;
FIG. **3** is a left-side elevational view thereof;
FIG. **4** is a right-side elevational view thereof;
FIG. **5** is a top plan view thereof;
FIG. **6** is a bottom plan view thereof;
FIG. **7** is a front, right-side, top perspective view thereof; and,
FIG. **8** is a rear, left-side, top perspective view thereof.

The broken lines depict environmental subject matter only and form no part of the claimed design.

1 Claim, 7 Drawing Sheets





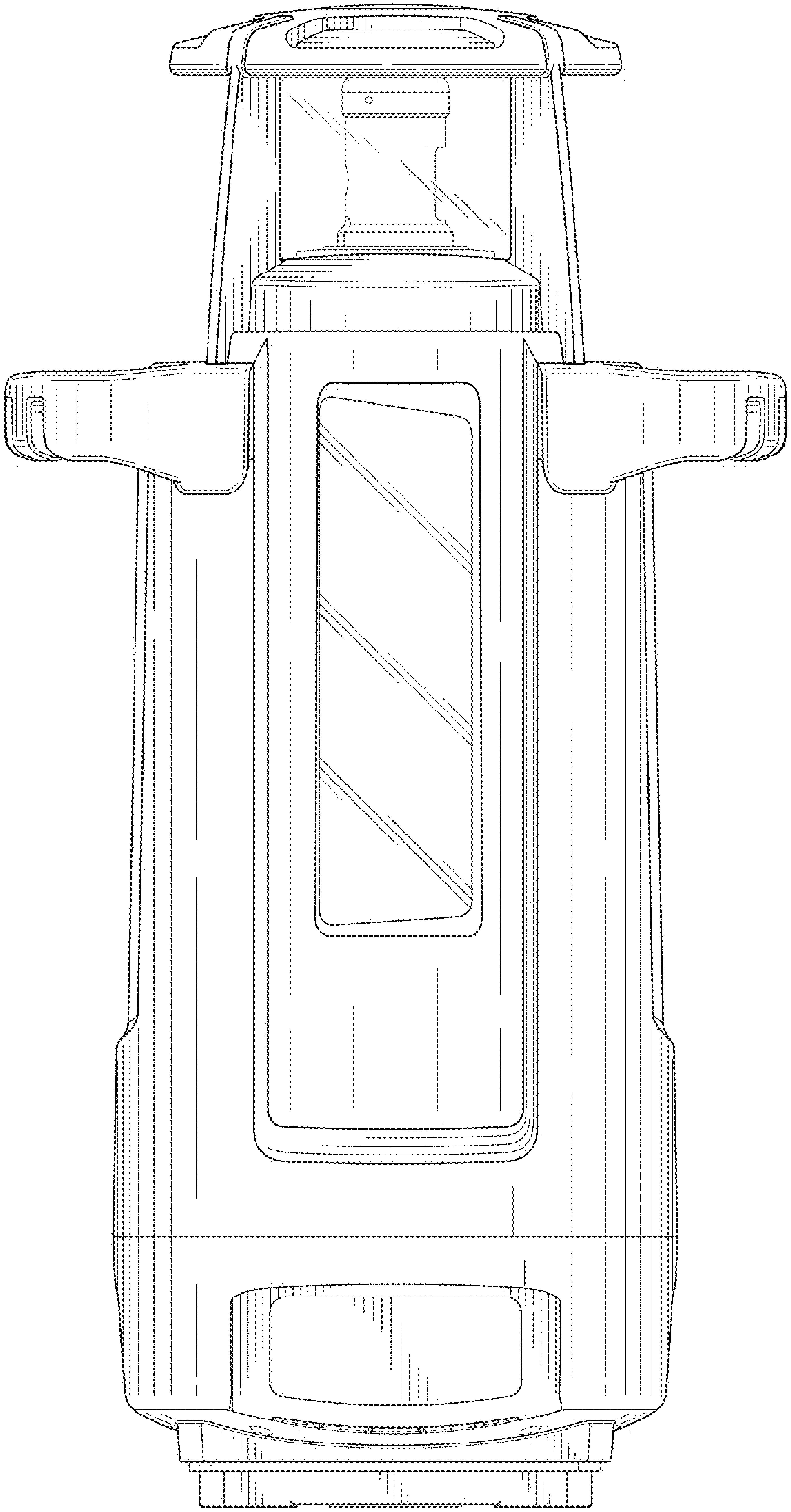


FIG. 1

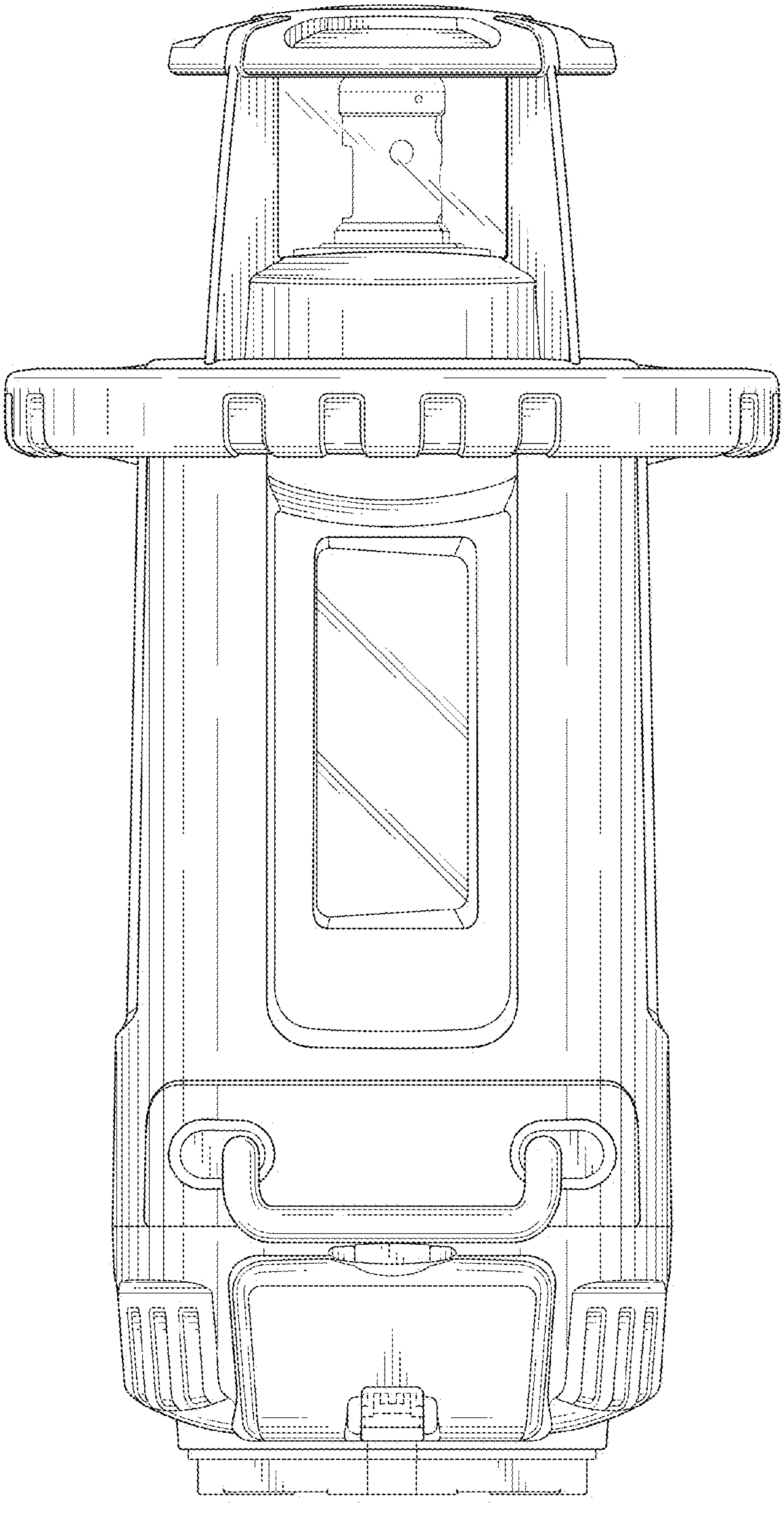


FIG. 2

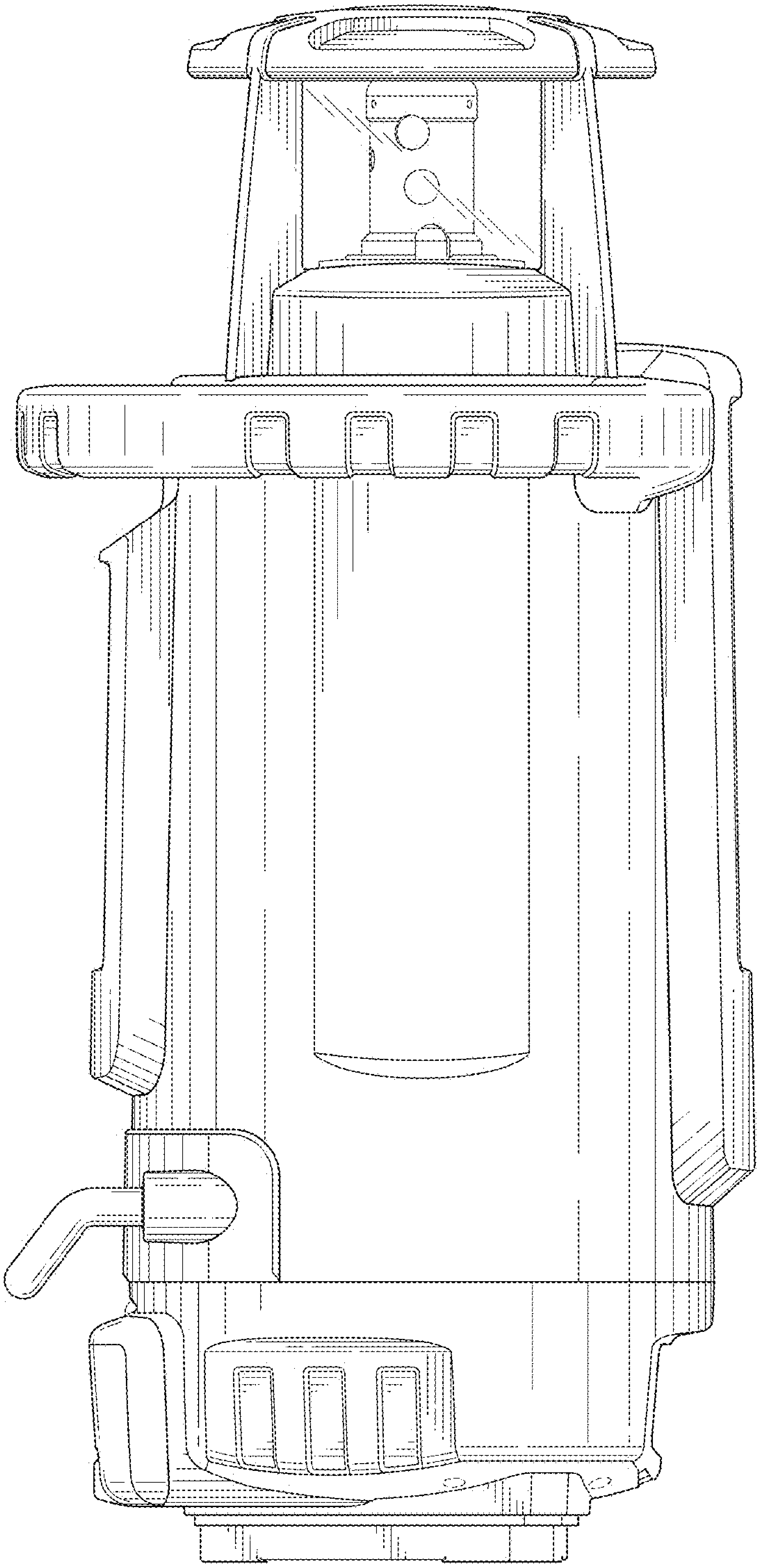


FIG. 3

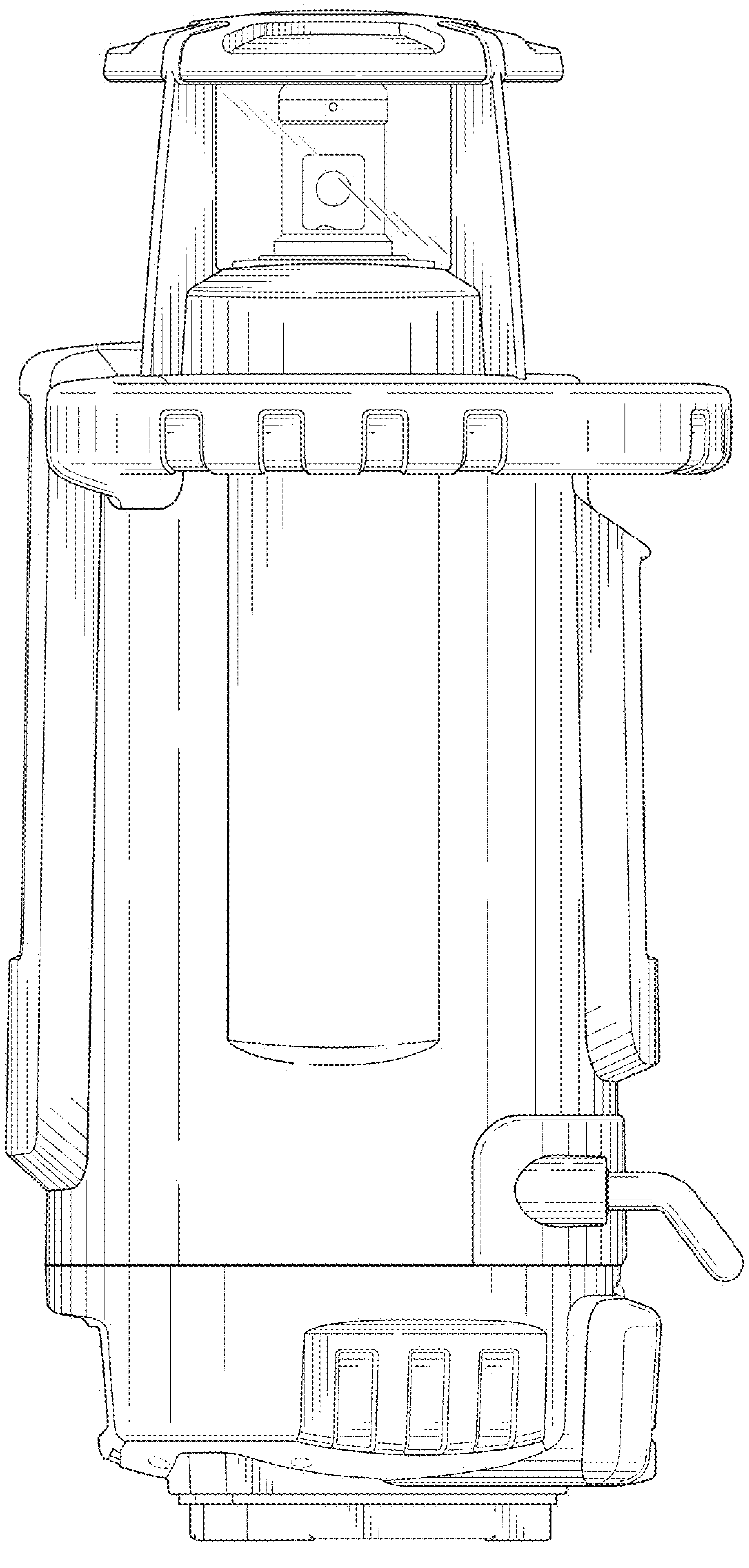


FIG. 4

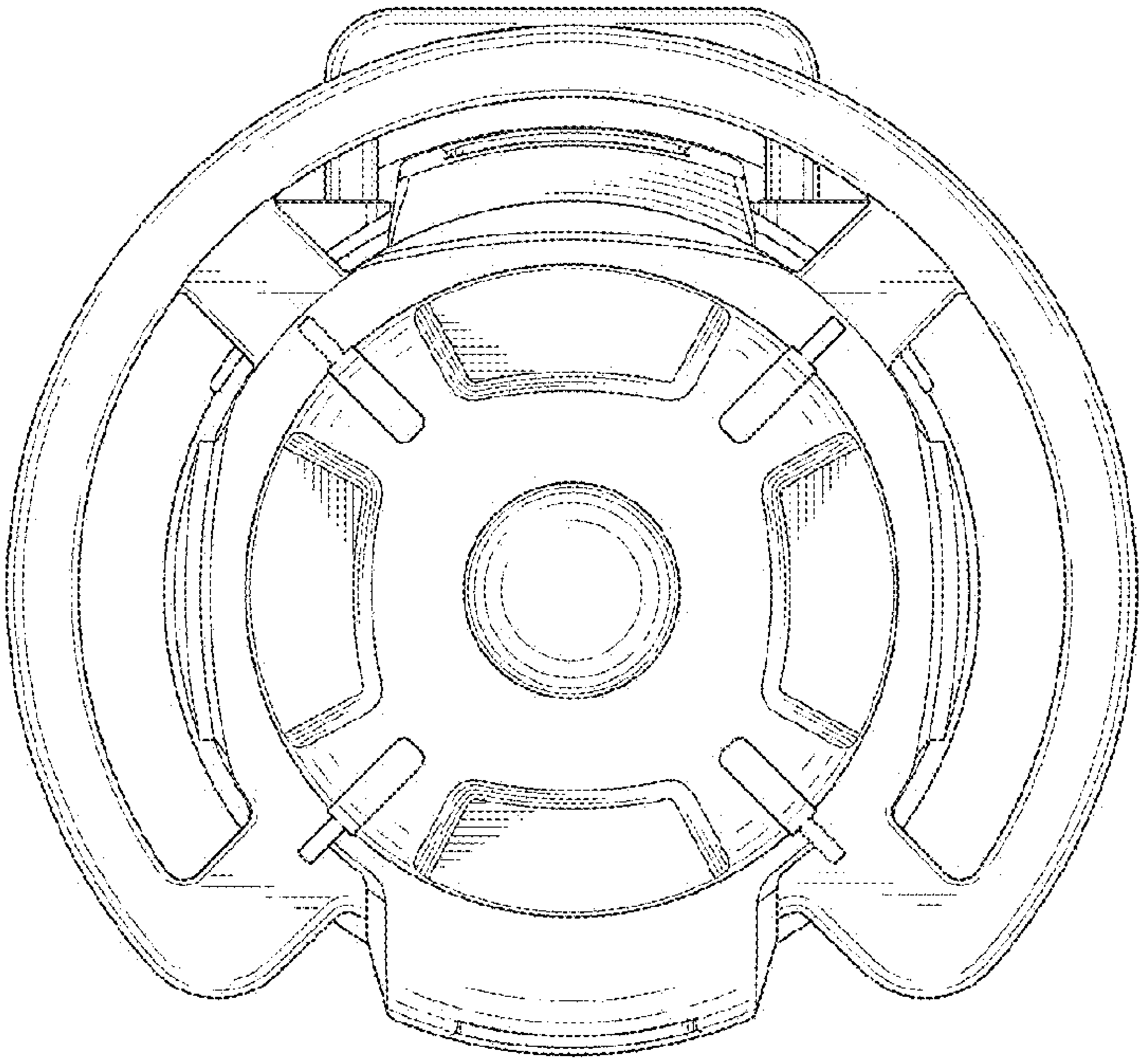


FIG. 5

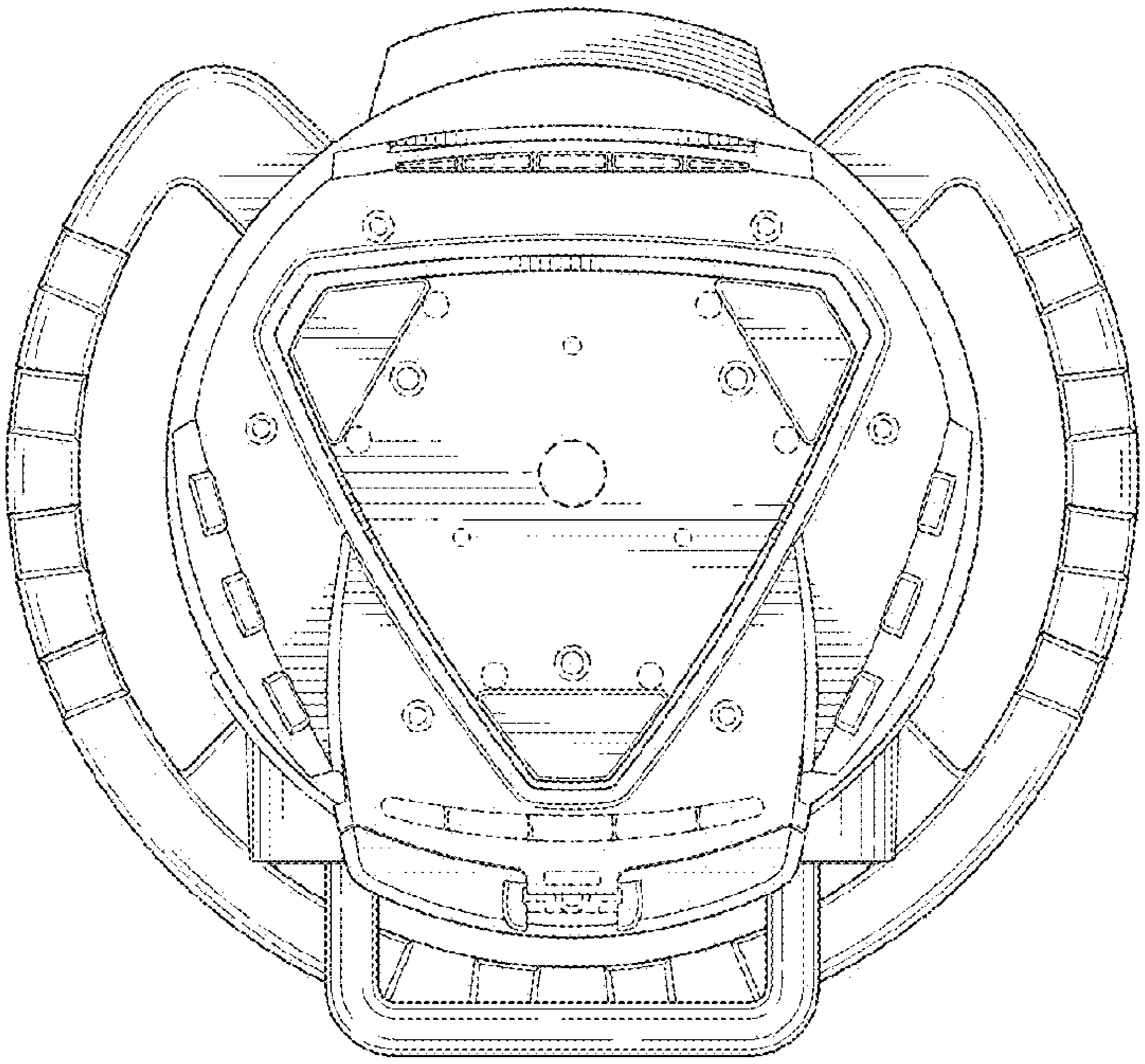


FIG. 6

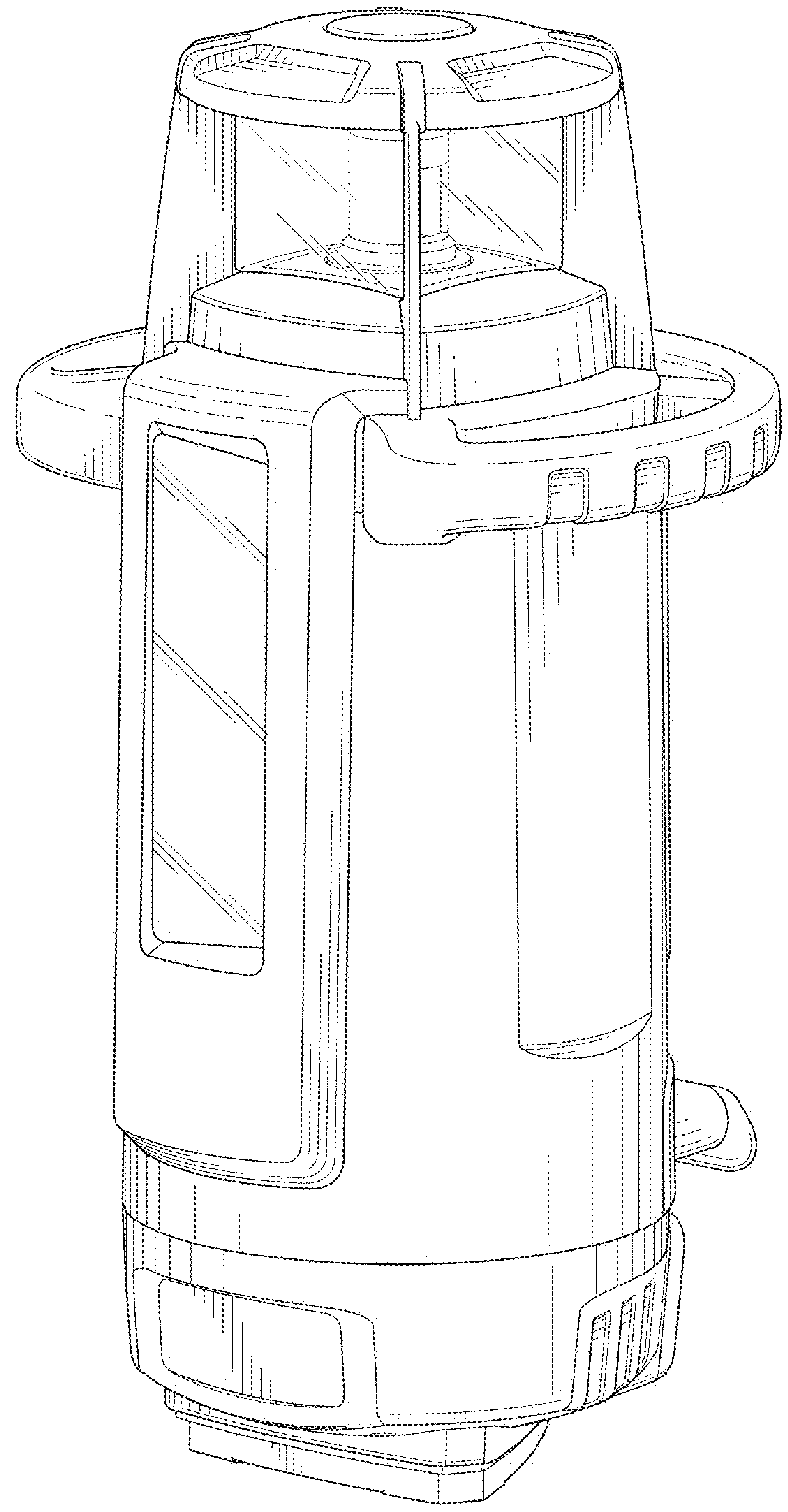


FIG. 7

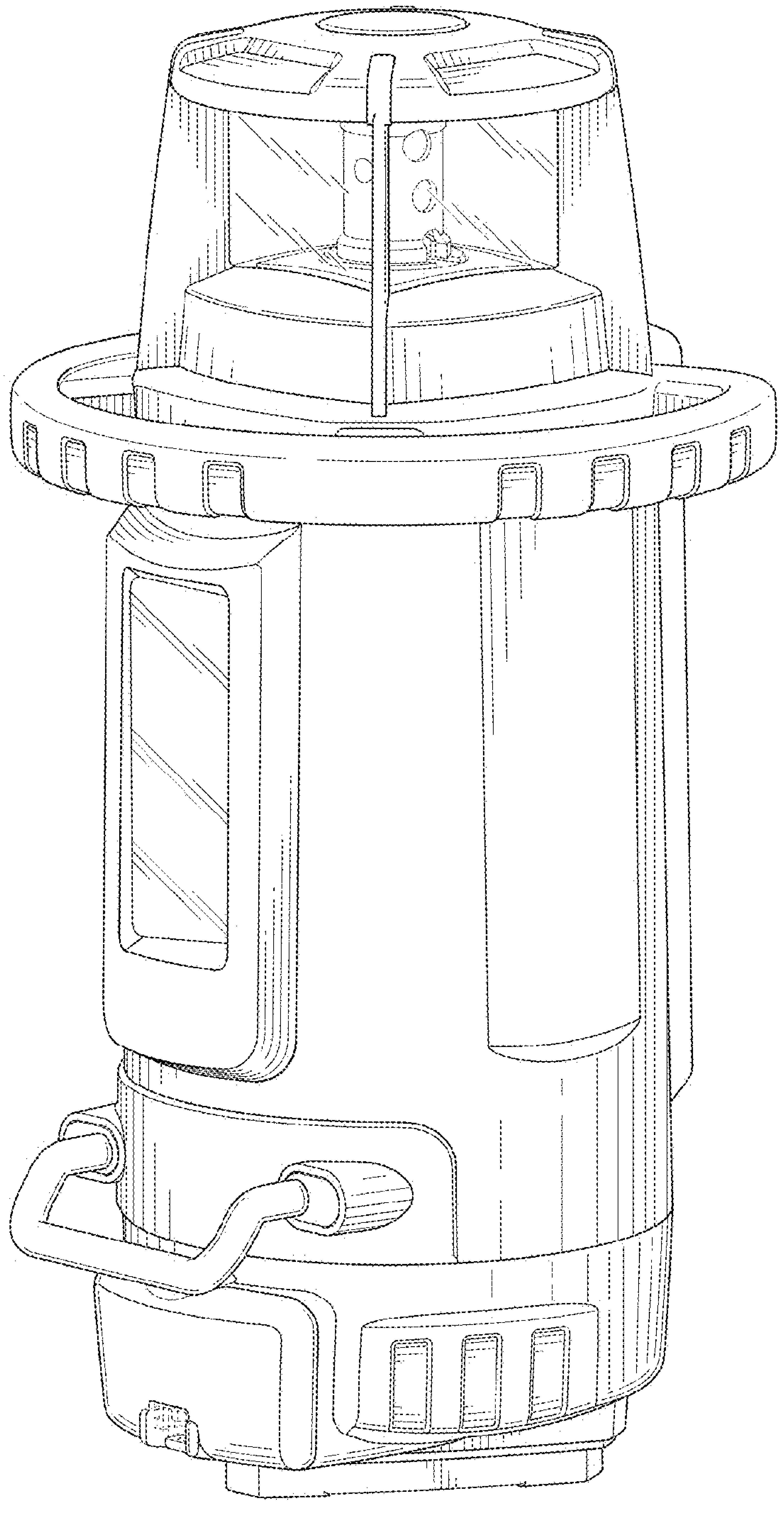


FIG. 8